



MICROCHIP

QUALIFICATION REPORT SUMMARY

PCN #: CAAN-12PCKT688

**Date:
March 09, 2026**

Qualification of MTAI as an additional final test site for A3P060-1FG144T, A3P060-1FGG144T, A3P060-FG144T and A3P060-FGG144T catalog part numbers (CPN) available in 144L LFBGA (13x13x1.55mm) package.

Purpose: Qualification of MTAI as an additional final test site for A3P060-1FG144T, A3P060-1FGG144T, A3P060-FG144T and A3P060-FGG144T catalog part numbers (CPN) available in 144L LFBGA (13x13x1.55mm) package.

CCB No.: 7768

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria	Result
Bin and Yield Comparison	Test the same units at existing and destination locations and compare Bin and Yield data.	3000	1	$\leq 0.1\%$	Passed
Original Final Test Site Characterization	Characterize good devices at the original test site with DC items and measurable functional test items.	33	1	$\leq 10\%$	Passed
Destination Final Test Site Cross Correlation	Run untested devices from the destination test site with same FT program; keep the good devices and rejects separate by bins and send all devices to the original test site for correlation.	33	1	$\leq 10\%$	Passed
Correlation Lot report	Yield at each step and reject analysis between systems. 33 units are tested as lot correlation • Accept on yield match within 0.1%	33	1	$\leq 10\%$	Passed